

Michelly De Souza

List of Publications by Year in descending order

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docs citations

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585
citing authors

#	ARTICLE	IF	CITATIONS
1	Variability Modeling in Triple-Gate Junctionless Nanowire Transistors. IEEE Transactions on Electron Devices, 2022, 69, 4730-4736.	3.0	1
2	Experimental Demonstration of $\hat{\text{I}}^{\text{C}}$ -Gate SOI Nanowire MOS Transistorsâ€™™ Mobility Variation Induced by Substrate Bias. IEEE Transactions on Electron Devices, 2022, 69, 4022-4028.	3.0	0
3	On the Application of Junctionless Nanowire Transistors in Basic Analog Building Blocks. IEEE Nanotechnology Magazine, 2021, 20, 234-242.	2.0	4
4	Strategy for Simulation of Analog Circuits with GCSOI MOSFET using BSIM SOI model. , 2021, , .		0
5	Junctionless Nanowire Transistors Based Wilson Current Mirror Configuration. , 2021, , .		3
6	Analysis of Capacitances in Asymmetric Self-Cascode SOI nMOSFETs. , 2021, , .		1
7	Junctionless Nanowire Transistors Based Common-Source Current Mirror. , 2021, , .		2
8	Experimental Assessment of Variability in Junctionless Nanowire nMOS Transistors. , 2021, , .		3
9	Analysis of the Thermal Properties of Self-Cascode Structures Composed by UTBB Transistors. , 2020, , .		0
10	Temperature, Silicon Thickness and Intrinsic Length Influence on the Operation of Lateral SOI PIN Photodiodes. Journal of Integrated Circuits and Systems, 2020, 15, 1-5.	0.4	0
11	Analysis of Mobility in Graded-Channel SOI Transistors Aiming at Circuit Simulation. Journal of Integrated Circuits and Systems, 2020, 15, 1-5.	0.4	1
12	Analysis of Current Mirrors with Asymmetric Self-Cascode Association of SOI MOSFETs through SPICE Simulations. Journal of Integrated Circuits and Systems, 2020, 15, 1-5.	0.4	0
13	Junctionless nanowire transistors parameters extraction based on drain current measurements. Solid-State Electronics, 2019, 158, 37-45.	1.4	5
14	FOSS EKV2.6 Verilog-A Compact MOSFET Model. , 2019, , .		4
15	Harmonic Distortion in Symmetric and Asymmetric Self-Cascodes of UTBB FD SOI Planar MOSFETs. , 2019, , .		0
16	Subthreshold Operation of Self-Cascode Structure Using UTBB FD SOI Planar MOSFETs. , 2019, , .		1
17	Modeling the Interface Trap Density Influence on Junctionless Nanowire Transistors Behavior. , 2018, , .		2
18	Back bias influence on low-frequency noise of n-type nanowires SOI MOSFETs. , 2018, , .		0

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19	Influence of the Intrinsic Length on the Behavior of PIN Diodes Fabricated on SOI Substrates Working as Solar Cells. , 2018, , .		1
20	Asymmetric Self-Cascode Current-Voltage Constructing Algorithm for Analog Figures-of-Merit Extraction. , 2018, , .		0
21	Accounting for Series Resistance in the Compact Model of Triple-Gate Junctionless Nanowire Transistors. , 2018, , .		4
22	Numerical Simulation and Analysis of Transistor Channel Length and Doping Mismatching in GC SOI nMOSFETs Analog Figures of Merit. , 2018, , .		0
23	Linearity Enhancement in Asymmetric Self-Cascode Composed by FD SOI nMOSFETs. , 2018, , .		0
24	Static and dynamic compact analytical model for junctionless nanowire transistors. Journal of Physics Condensed Matter, 2018, 30, 334002.	1.8	5
25	Design benefits of self-cascode configuration for analog applications in 28 FDSOI. , 2018, , .		1
26	Physical Insights on the Dynamic Response of SOI n- and p-Type Junctionless Nanowire Transistors. Journal of Integrated Circuits and Systems, 2018, 13, 1-7.	0.4	3
27	Influence of Geometrical Parameters on the DC Analog Behavior of the Asymmetric Self-Cascode FD SOI nMOSFETs. Journal of Integrated Circuits and Systems, 2018, 13, 1-7.	0.4	0
28	Analysis of Mismatching on the Analog Characteristics of GC SOI MOSFETs. Journal of Integrated Circuits and Systems, 2018, 13, 1-8.	0.4	0
29	Analysis of the substrate bias effect on the interface trapped charges in junctionless nanowire transistors through low-frequency noise characterization. Microelectronic Engineering, 2017, 178, 17-20.	2.4	10
30	A New Method for Series Resistance Extraction of Nanometer MOSFETs. IEEE Transactions on Electron Devices, 2017, 64, 2797-2803.	3.0	16
31	A new method for junctionless transistors parameters extraction. , 2017, , .		0
32	Improved analog performance of SOI Nanowire nMOSFETs Self-Cascode through back-biasing. , 2017, , .		1
33	Analysis of p-type Junctionless nanowire transistors with different crystallographic orientations. , 2017, , .		0
34	Lateral spacers influence on the effective channel length of junctionless nanowire transistors. , 2017, , .		4
35	Analog performance of self-cascode SOI nanowires nMOSFETs aiming at low-power applications. , 2017, , .		0
36	Channel width influence on the analog performance of the asymmetric self-cascode FD SOI nMOSFETs. , 2017, , .		1

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37	Experimental evaluation of mismatching on the analog characteristics of GC SOI MOSFETs. , 2017, , .		1
38	Experimental comparative analysis between junctionless and inversion mode nanowire transistors down to 10 nm-long channel lengths. , 2017, , .		0
39	Effect of the back bias on the analog performance of standard FD and UTBB transistors-based self-cascode structures. Semiconductor Science and Technology, 2017, 32, 095005.	2.0	2
40	Experimental and simulation analysis of electrical characteristics of commonâ€source current mirrors implemented with asymmetric selfâ€cascode siliconâ€onâ€insulator nâ€channel metalâ€oxideâ€semiconductor 1.4 fieldâ€effect transistors. IET Circuits, Devices and Systems, 2016, 10, 349-355.		2
41	A new series resistance extraction method for junctionless nanowire transistors. , 2016, , .		3
42	Influence of the crystal orientation on the operation of junctionless nanowire transistors. , 2016, , .		2
43	Low power highly linear temperature sensor based on SOI lateral PIN diodes. , 2016, , .		4
44	Use of back gate bias to improve the performance of n- and p-type UTBB transistors-based self-cascode structures applied to current mirrors. , 2016, , .		3
45	Physical insights on the dynamic response of junctionless nanowire transistors. , 2016, , .		1
46	Low-frequency noise in asymmetric self-cascode FD SOI nMOSFETs. , 2016, , .		0
47	Improved operation of graded-channel SOI nMOSFETs down to liquid helium temperature. Semiconductor Science and Technology, 2016, 31, 114005.	2.0	4
48	Junctionless nanowire transistors operation at temperatures down to 4.2 K. Semiconductor Science and Technology, 2016, 31, 114001.	2.0	17
49	Low-frequency noise of submicron graded-channel SOI nMOSFETs at high temperature. , 2016, , .		0
50	On the improvement of DC analog characteristics of FD SOI transistors by using asymmetric self-cascode configuration. Solid-State Electronics, 2016, 117, 152-160.	1.4	18
51	Errata to â€Surface-Potential-Based Drain Current Analytical Model for Triple-Gate Junctionless Nanowire Transistorsâ€[Dec 12 3510-3518]. IEEE Transactions on Electron Devices, 2016, 63, 527-527.	3.0	1
52	Analytical Model for the Dynamic Behavior of Triple-Gate Junctionless Nanowire Transistors. IEEE Transactions on Electron Devices, 2016, 63, 856-863.	3.0	24
53	Analog performance improvement of self-cascode structures composed by UTBB transistors using back gate bias. , 2015, , .		6
54	Quasi-static analytical model for the dynamic operation of triple-gate junctionless nanowire transistors. , 2015, , .		1

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55	Advantages of subthreshold operation of asymmetric self-cascode SOI transistors aiming at analog circuit applications. , 2015, , .		2
56	On the origin of low-frequency noise of submicron Graded-Channel fully depleted SOI nMOSFETs. , 2015, , .		1
57	Use of back gate bias to enhance the analog performance of planar FD and UTBB SOI transistors-based self-cascode structures. , 2015, , .		3
58	Effective channel length in Junctionless Nanowire Transistors. , 2015, , .		13
59	Extraction of the interface trap density energetic distribution in SOI Junctionless Nanowire Transistors. Microelectronic Engineering, 2015, 147, 23-26.	2.4	11
60	Ultra-low-power diodes using junctionless nanowire transistors. , 2015, , .		1
61	Improved analog operation of junctionless nanowire transistors using back bias. , 2015, , .		5
62	Asymmetric Self-Cascode versus Graded-Channel SOI nMOSFETs for analog applications. , 2015, , .		1
63	Effect of channel doping concentration on the harmonic distortion of asymmetric n- and p-type self-cascode MOSFETs. , 2015, , .		0
64	Effective mobility analysis of n- and p-types SOI junctionless nanowire transistors. , 2014, , .		2
65	Analysis of harmonic distortion of asymmetric self-cascode association of SOI nMOSFETs operating in saturation. , 2014, , .		3
66	Effect of high temperature on analog parameters of Asymmetric Self-Cascode SOI nMOSFETs. , 2014, , .		0
67	Analog operation of Junctionless Nanowire Transistors down to liquid helium temperature. , 2014, , .		0
68	Analog performance of short-channel asymmetric self-cascode of junctionless nanowire nMOS transistors. , 2014, , .		1
69	Effect of the temperature on on Junctionless Nanowire Transistors electrical parameters down to 4K. , 2014, , .		6
70	Asymmetric self-cascode FD SOI nMOSFETS harmonic distortion at cryogenic temperatures. , 2014, , .		1
71	Compact core model for Symmetric Double-Gate Junctionless Transistors. Solid-State Electronics, 2014, 94, 91-97.	1.4	21
72	Substrate Bias Influence on the Operation of Junctionless Nanowire Transistors. IEEE Transactions on Electron Devices, 2014, 61, 1575-1582.	3.0	36

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73	Low-frequency noise and effective trap density of short channel p- and n-types junctionless nanowire transistors. Solid-State Electronics, 2014, 96, 22-26.	1.4	11
74	Technological parameters scaling influence on the analog performance of Graded-Channel SOI nMOSFET transistors. , 2014, , .		3
75	Charge-based continuous model for long-channel Symmetric Double-Gate Junctionless Transistors. Solid-State Electronics, 2013, 85, 59-63.	1.4	37
76	Approximate analytical expression for the tersminal voltage in multi-exponential diode models. Solid-State Electronics, 2013, 89, 7-11.	1.4	7
77	A physically-based threshold voltage definition, extraction and analytical model for junctionless nanowire transistors. Solid-State Electronics, 2013, 90, 12-17.	1.4	44
78	Asymmetric channel doping profile and temperature reduction influence on the performance of current mirrors implemented with FD SOI nMOSFETs. Microelectronics Reliability, 2013, 53, 848-855.	1.7	5
79	The influence of the substrate bias in Junctionless nanowire transistors. , 2013, , .		0
80	Non-linear behavior of Junctionless nanowire transistors operating in the linear regime. , 2013, , .		1
81	Low frequency noise in submicron Graded-Channel SOI MOSFETs. , 2013, , .		3
82	Harmonic distortion analysis of short channel junctionless nanowire transistors operating as amplifiers. , 2013, , .		2
83	Analysis of charges densities in multiple-gates SOI nMOS junctionless. , 2013, , .		2
84	Analytical model for potential in double-gate juntionless transistors. , 2013, , .		1
85	Trap density characterization through low-frequency noise in junctionless transistors. Microelectronic Engineering, 2013, 109, 79-82.	2.4	11
86	Performance of Junctionless Nanowire MOSFET as a Quasi-Linear Resistor. ECS Transactions, 2013, 53, 115-120.	0.5	1
87	Analog Behavior of Submicron Graded-Channel SOI MOSFETs Varying Channel Length, Doping Concentration and Temperature. ECS Transactions, 2013, 53, 149-154.	0.5	1
88	Analysis of the leakage current in junctionless nanowire transistors. Applied Physics Letters, 2013, 103, .	3.3	25
89	Channel length influence on the analog characteristics of asymmetric self-cascode association of SOI transistors. , 2013, , .		10
90	Drain Current and Short Channel Effects Modeling in Junctionless Nanowire Transistors. Journal of Integrated Circuits and Systems, 2013, 8, 116-124.	0.4	8

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91	Liquid Helium Temperature Operation of Graded-Channel SOI nMOSFETs. ECS Transactions, 2012, 49, 135-144.	0.5	0
92	Analog performance of asymmetric self-cascode p-channel fully depleted SOI transistors. , 2012, , .		6
93	Intrinsic Gate Capacitances of n-type Junctionless Nanowire Transistors Using a Three-Dimensional Device Simulation and Experimental Measurements. ECS Transactions, 2012, 49, 231-239.	0.5	1
94	Accounting for Short Channel Effects in the Drain Current Modeling of Junctionless Nanowire Transistors. ECS Transactions, 2012, 49, 207-214.	0.5	2
95	Comparative Study of Biaxial and Uniaxial Mechanical Stress Influence on the Low Frequency Noise of Fully Depleted SOI nMOSFETs Operating in Triode and Saturation Regime. ECS Transactions, 2012, 49, 77-83.	0.5	0
96	Application of Junctionless Nanowire Transistor in the Self-Cascode Configuration to Improve the Analog Performance. ECS Transactions, 2012, 49, 215-222.	0.5	8
97	The role of the incomplete ionization on the operation of Junctionless Nanowire Transistors. , 2012, , .		2
98	Analysis of gate capacitance of n-type junctionless transistors using three-dimensional device simulations. , 2012, , .		11
99	Liquid helium temperature analog operation of asymmetric self-cascode FD SOI MOSFETs. , 2012, , .		4
100	Low-Frequency Noise of nMOS and pMOS short channel junctionless nanowire transistors. , 2012, , .		8
101	The zero temperature coefficient in junctionless nanowire transistors. Applied Physics Letters, 2012, 101, 062101.	3.3	27
102	Surface-Potential-Based Drain Current Analytical Model for Triple-Gate Junctionless Nanowire Transistors. IEEE Transactions on Electron Devices, 2012, 59, 3510-3518.	3.0	94
103	Drain current model for junctionless nanowire transistors. , 2012, , .		3
104	Analysis of temperature variation influence on the analog performance of 45° rotated triple-gate nMuGFETs. Solid-State Electronics, 2012, 70, 39-43.	1.4	4
105	Modeling of Thin-Film Lateral SOI PIN Diodes with an Alternative Multi-Branch Explicit Current Model. Journal of Integrated Circuits and Systems, 2012, 7, 92-99.	0.4	1
106	Impact of the Series Resistance in the I-V Characteristics of Junctionless Nanowire Transistors and its dependence on the Temperature. Journal of Integrated Circuits and Systems, 2012, 7, 121-129.	0.4	46
107	Characterization of Thin-Film SOI PIN Diodes from Cryogenic to Above Room Temperatures Using an Explicit I-V Multi-Branch Model. ECS Transactions, 2011, 39, 171-178.	0.5	2
108	Analysis of the Low-Frequency Noise of Junctionless Nanowire Transistors operating in saturation. , 2011, , .		5

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109	Asymmetric self-cascode configuration to improve the analog performance of SOI nMOS transistors. , 2011, , .		21
110	Cryogenic Operation of Junctionless Nanowire Transistors. IEEE Electron Device Letters, 2011, 32, 1322-1324.	3.9	51
111	Threshold voltage in junctionless nanowire transistors. Semiconductor Science and Technology, 2011, 26, 105009.	2.0	104
112	An explicit multi-exponential model for semiconductor junctions with series and shunt resistances. Microelectronics Reliability, 2011, 51, 2044-2048.	1.7	29
113	Junctionless Multiple-Gate Transistors for Analog Applications. IEEE Transactions on Electron Devices, 2011, 58, 2511-2519.	3.0	234
114	Impact of Substrate Rotation and Temperature on the Mobility and Series Resistance of Triple-Gate SOI nMOSFETs. ECS Transactions, 2011, 39, 223-230.	0.5	2
115	Performance of Ultra-Low-Power SOI CMOS Diodes Operating at Low Temperatures. ECS Transactions, 2011, 35, 325-330.	0.5	1
116	Comparison between SOI nMOSFET's under Uniaxial and Biaxial Mechanical Stress in Analog Applications. ECS Transactions, 2011, 39, 37-44.	0.5	1
117	Monte Carlo simulation of graded-channel fully depleted SOI nMOSFETs. , 2011, , .		0
118	Temperature and Silicon Film Thickness Influence on the Operation of Lateral SOI PIN Photodiodes for Detection of Short Wavelengths. Journal of Integrated Circuits and Systems, 2011, 6, 107-113.	0.4	10
119	Analog Operation Temperature Dependence of nMOS Junctionless Transistors Focusing on Harmonic Distortion. Journal of Integrated Circuits and Systems, 2011, 6, 114-121.	0.4	15
120	Analysis of the Low-Frequency Noise in Graded-Channel and Standard SOI nMOSFET. ECS Transactions, 2010, 31, 359-366.	0.5	1
121	Analysis of Lateral SOI PIN Diodes for the Detection of Blue and UV Wavelengths in a Wide Temperature Range. ECS Transactions, 2010, 31, 199-206.	0.5	6
122	Parameter Extraction in Quadratic Exponential Junction Model with Series Resistance using Global Lateral Fitting. ECS Transactions, 2010, 31, 369-376.	0.5	7
123	Analog operation of junctionless transistors at cryogenic temperatures. , 2010, , .		9
124	Comparison between the behavior of submicron graded-channel SOI nMOSFETs with fully- and partially-depleted operations in a wide temperature range. , 2010, , .		2
125	Electrical characterization of SOI solar cells in a wide temperature range. , 2010, , .		1
126	Thin-Film Lateral SOI PIN Diodes for Thermal Sensing Reaching the Cryogenic Regime. Journal of Integrated Circuits and Systems, 2010, 5, 160-167.	0.4	14

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127	On the Performance of Thin-Film Lateral SOI PIN Diodes as Thermal Sensors in a Wide Temperature Range. ECS Transactions, 2009, 23, 397-404.	0.5	3
128	Performance of Common-Source, Cascode and Wilson Current Mirrors Implemented with Graded-Channel SOI nMOSFETs in a Wide Temperature Range. ECS Transactions, 2009, 19, 265-270.	0.5	1
129	Analysis of source-follower buffers implemented with graded-channel SOI nMOSFETs operating at cryogenic temperatures. Cryogenics, 2009, 49, 599-604.	1.7	5
130	Advantages of graded-channel SOI nMOSFETs for application as source-follower analog buffer. Solid-State Electronics, 2008, 52, 1933-1938.	1.4	10
131	Channel Length Influence on the Performance of Source-Follower Buffers Implemented with Graded-Channel SOI nMOSFETs. ECS Transactions, 2008, 14, 263-272.	0.5	1
132	Study of Matching Properties of Graded-Channel SOI MOSFETs. Journal of Integrated Circuits and Systems, 2008, 3, 69-75.	0.4	8
133	Low temperature influence on the uniaxially strained FD SOI nMOSFETs behavior. Microelectronic Engineering, 2007, 84, 2121-2124.	2.4	3
134	A charge-based continuous model for submicron graded-channel nMOSFET for analog circuit simulation. Solid-State Electronics, 2005, 49, 1683-1692.	1.4	10
135	Graded-Channel SOI nMOSFET Model Valid for Harmonic Distortion Evaluation. , 0, , .		2